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NONFERROUS METALS INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

YS/T 26-1992

Test method for silicon wafer edge

硅片边缘轮郭检验方法

(English Translation)

Issued on: March 9, 1992

Issued by: China Nonferrous Metals Industry Corporation

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Document data

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Sector: National Recommended (industry standard).

Issuing body: China Nonferrous Metals Industry Corporation.

Date of issue: 1992-03-09.

Date of implementation: 1993-01-01.

Status: obsolete, replaced by YS/T 26-2016.

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https://chinastandards.org/standards/ys-t-26-1992